

# 1-Mbit (128 K × 8) Static RAM

### **Features**

- Pin- and function-compatible with CY7C1018CV33
- High speed

  □ t<sub>AA</sub> = 10 ns
- Low Active Power
  □ I<sub>CC</sub> = 60 mA @ 10 ns
- Low CMOS Standby Power
  □ I<sub>SB2</sub> = 3 mA
- 2.0V Data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Center power/ground pinout
- Easy memory expansion with  $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  options
- Available in Pb-free 32-pin 300-Mil wide Molded SOJ

### **Functional Description**

The CY7C1018DV33 is a high-performance CMOS static RAM organized as 131,072 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable (CE), an active LOW Output Enable (OE), and tri-state drivers. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

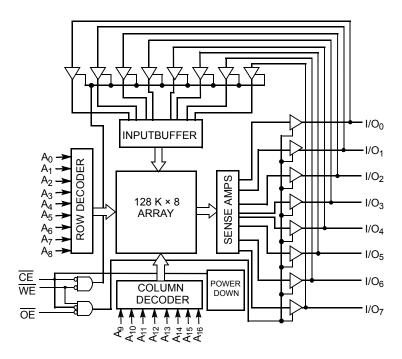
Writing to the device is accomplished by taking Chip Enable  $(\overline{CE})$  and Write Enable  $(\overline{WE})$  inputs LOW. Data on the eight I/O pins  $(I/O_0$  through  $I/O_7)$  is then written into the location specified on the address pins  $(A_0$  through  $A_{16}$ ).

Reading from the device is accomplished by taking Chip Enable (CE) and Output Enable (OE) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input/output pins (I/O $_0$  through I/O $_7$ ) are <u>placed</u> in a high-impedance state when the device is deselected (CE HIGH), the outputs are <u>disabled</u> (OE HIGH), or during a write operation (CE LOW, and WE LOW).

The CY7C1018DV33 is available in Pb-free 32-pin 300-Mil wide Molded SOJ.

## **Logic Block Diagram**



[+] Feedback

# CY7C1018DV33



### **Contents**

Selection Guide	
Pin Configuration	3
Maximum Ratings	4
Operating Range	
DC Electrical Characteristics	4
Capacitance	5
Thermal Resistance	5
AC Test Loads and Waveforms	5
AC Switching Characteristics	
Data Retention Characteristics	
Data Retention Waveform	
Switching Waveforms	
Truth Table	

Ordering Information	11
Ordering Code Definitions	11
Package Diagram	
Acronyms	13
Document Conventions	13
Units of Measure	13
Document History Page	14
Sales, Solutions, and Legal Information	
Worldwide Sales and Design Support	
Products	
PSoC Solutions	15

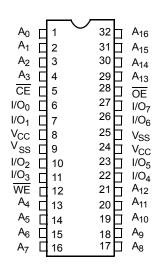


### **Selection Guide**

	-10 (Industrial)	Unit
Maximum Access Time	10	ns
Maximum Operating Current	60	mA
Maximum Standby Current	3	mA

## **Pin Configuration**

Figure 1. 32-pin SOJ Top View





## **Maximum Ratings**

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage Temperature ......—65 °C to +150 °C

Ambient Temperature with

Power Applied .....—55 °C to +125 °C

Power Applied ......55 °C to +125 °C

Supply Voltage on V<sub>CC</sub> to Relative GND <sup>[1]</sup> .....–0.3 V to + 4.6 V DC Voltage Applied to Outputs <sup>[1]</sup>

DC Input Voltage [1]	0.3 V to V <sub>CC</sub> + 0.3 V
Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	> 2001V
Latch-up Current	> 200 mA

## **Operating Range**

Range	Ambient Temperature	V <sub>CC</sub>	Speed
Industrial	–40 °C to +85 °C	$3.3 \text{ V} \pm 0.3 \text{ V}$	10 ns

### **DC Electrical Characteristics**

Over the Operating Range

Davamatav	Description	Took Conditions	Test Conditions		lustrial)	11:::4
Parameter	Description	rest Conditions			Max	Unit
V <sub>OH</sub>	Output HIGH Voltage	Min V <sub>CC</sub> , I <sub>OH</sub> = -4.0 mA		2.4	_	V
$V_{OL}$	Output LOW Voltage	Min $V_{CC}$ , $I_{OL}$ = 8.0 mA		-	0.4	V
V <sub>IH</sub>	Input HIGH Voltage			2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW Voltage [1]			-0.3	0.8	V
I <sub>IX</sub>	Input Leakage Current	GND ≤ V <sub>IN</sub> ≤ V <sub>CC</sub>		-1	+1	μА
I <sub>OZ</sub>	Output Leakage Current	$GND \le V_{IN} \le V_{CC}$ , Output Disabled		<b>–1</b>	+1	μΑ
I <sub>CC</sub>	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max, I <sub>OUT</sub> = 0 mA,	100 MHz	-	60	mA
		$f = f_{MAX} = 1/t_{RC}$	83 MHz	-	55	mA
			66 MHz	-	45	mA
			40 MHz	-	30	mA
I <sub>SB1</sub>	Automatic CE Power-down Current–TTL Inputs	$\begin{aligned} &\text{Max V}_{CC},  \overline{\text{CE}} \geq \text{V}_{\text{IH}} \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}},  \text{f} = \text{f}_{\text{MAX}} \end{aligned}$		_	10	mA
I <sub>SB2</sub>	Automatic CE Power-down Current–CMOS Inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \ \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V or V}_{\text{IN}} \leq 0.3 \text{ V, f} = \end{aligned}$	0	_	3	mA

Note

Document Number: 38-05465 Rev. \*F

<sup>1.</sup>  $V_{IL(min)} = -2.0 \text{ V}$  and  $V_{IH(max)} = V_{CC} + 1 \text{ V}$  for pulse durations of less than 5 ns.



## Capacitance

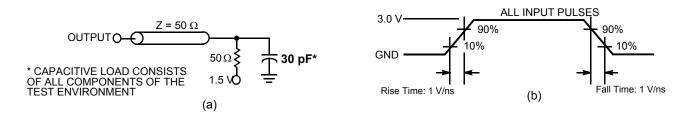
Parameter [2]	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 3.3 \text{V}$	8	pF
C <sub>OUT</sub>	Output Capacitance		8	pF

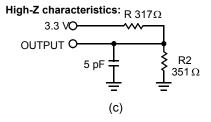
### **Thermal Resistance**

Parameter [2]	Description	Test Conditions	32-pin SOJ	Unit
$\Theta_{JA}$	Thermal Resistance (Junction to Ambient)	Still Air, soldered on a 3 $\times$ 4.5 inch, four-layer printed circuit board	57.61	°C/W
$\Theta_{\sf JC}$	Thermal Resistance (Junction to Case)		40.53	°C/W

### **AC Test Loads and Waveforms**

Figure 2. AC Test Loads and Waveforms [3]





### Notes

- 2. Tested initially and after any design or process changes that may affect these parameters.
- 3. AC characteristics (except High-Z) are tested using the load conditions shown in Figure 2 (a). High-Z characteristics are tested for all speeds using the test load shown in Figure 2 (c).

Document Number: 38-05465 Rev. \*F Page 5 of 15



### **AC Switching Characteristics**

Over the Operating Range

Parameter [4]	Decembrish	-10 (Inc	lustrial)	I I m!4
Parameter	Description		Max	Unit
Read Cycle		•		_
t <sub>power</sub> <sup>[5]</sup>	V <sub>CC</sub> (typical) to the first access	100	_	μS
t <sub>RC</sub>	Read cycle time	10	_	ns
t <sub>AA</sub>	Address to data valid	_	10	ns
t <sub>OHA</sub>	Data hold from address change	3	_	ns
t <sub>ACE</sub>	CE LOW to data valid	_	10	ns
t <sub>DOE</sub>	OE LOW to data valid	_	5	ns
t <sub>LZOE</sub>	OE LOW to low Z [6]	0	_	ns
t <sub>HZOE</sub>	OE HIGH to high Z [6, 7]	_	5	ns
t <sub>LZCE</sub>	CE LOW to low Z [6]	3	_	ns
t <sub>HZCE</sub>	CE HIGH to high Z [6, 7]	_	5	ns
t <sub>PU</sub> <sup>[8]</sup>	CE LOW to power-up	0	_	ns
t <sub>PD</sub> <sup>[8]</sup>	CE HIGH to power-down	_	10	ns
Write Cycle [9,	10]			•
t <sub>WC</sub>	Write cycle time	10	_	ns
t <sub>SCE</sub>	CE LOW to write end	8	_	ns
t <sub>AW</sub>	Address set-up to write end	8	_	ns
t <sub>HA</sub>	Address hold from write end	0	_	ns
t <sub>SA</sub>	Address set-up to write start	0	_	ns
t <sub>PWE</sub>	WE pulse width	7	_	ns
t <sub>SD</sub>	Data set-up to write end	5	_	ns
t <sub>HD</sub>	Data hold from write end	0	_	ns
t <sub>LZWE</sub>	WE HIGH to low Z <sup>[6]</sup>	3	_	ns
t <sub>HZWE</sub>	WE LOW to high Z [6, 7]	_	5	ns

- Notes
   Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.
   t<sub>POWER</sub> gives the minimum amount of time that the power supply should be at typical V<sub>CC</sub> values until the first memory access can be performed.
   At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZCE</sub>, t<sub>HZOE</sub> is less than t<sub>LZOE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZWE</sub> for any given device.
   t<sub>HZOE</sub>, t<sub>HZCE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in (c) of Figure 2 on page 5. Transition is measured when the outputs enter a high impedance state.
   This parameter is guaranteed by design and is not tested.
   The internal Write time of the memory is defined by the overlap of CE LOW and WE LOW. CE and WE must be LOW to initiate a Write, and the transition of any of these signals can terminate the Write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the Write.
   The minimum Write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.



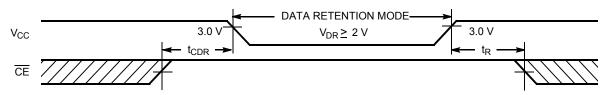
### **Data Retention Characteristics**

Over the Operating Range

Parameter	Description	Conditions	Min	Max	Unit
V <sub>DR</sub>	V <sub>CC</sub> for Data Retention		2	-	V
I <sub>CCDR</sub>	Data Retention Current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V} \text{ or } V_{IN} \le 0.3 \text{ V}$	_	3	mA
t <sub>CDR</sub> <sup>[11]</sup>	Chip Deselect to Data Retention Time		0	_	ns
t <sub>R</sub> <sup>[12]</sup>	Operation Recovery Time		t <sub>RC</sub>	_	ns

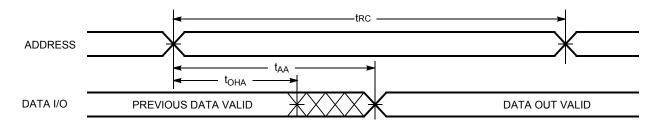
### **Data Retention Waveform**

Figure 3. Data Retention Waveform



## **Switching Waveforms**

Figure 4. Read Cycle No. 1 (Address Transition Controlled) [13, 14]



<sup>11.</sup> Tested initially and after any design or process changes that may affect these parameters.

Full device operation requires linear V<sub>CC</sub> ramp from V<sub>DR</sub> to V<sub>CC(min)</sub> ≥ 50 μs or stable at V<sub>CC(min)</sub> ≥ 50 μs.
 Device is continuously selected. OE, CE = V<sub>IL</sub>.
 WE is HIGH for Read cycle.



## Switching Waveforms (continued)

Figure 5. Read Cycle No. 2 (OE Controlled) [15, 16]

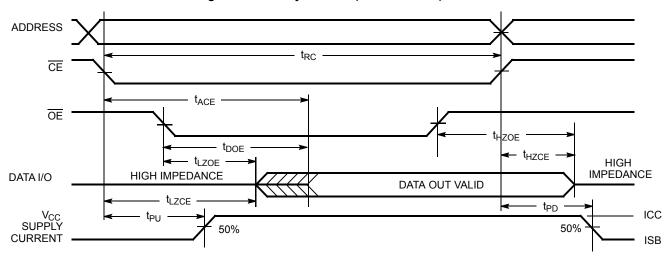
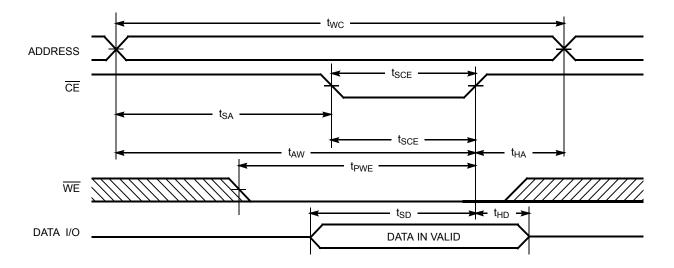


Figure 6. Write Cycle No. 1 (CE Controlled) [17, 18]



Notes

15. WE is HIGH for Read cycle.

16. Address valid prior to or coincident with CE transition LOW.

17. Data I/O is high impedance if OE = V<sub>IH</sub>.

18. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.



## Switching Waveforms (continued)

Figure 7. Write Cycle No. 2 (WE Controlled, OE HIGH During Write) [19, 20]

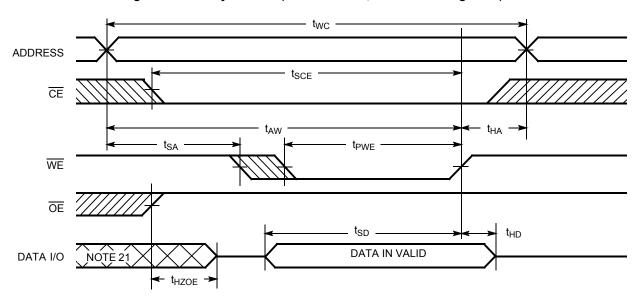
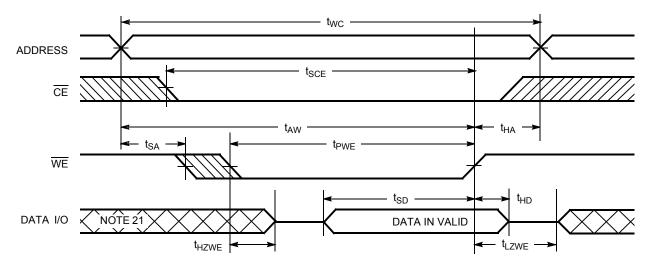


Figure 8. Write Cycle No. 3 ( $\overline{\text{WE}}$  Controlled,  $\overline{\text{OE}}$  LOW) [20, 22]



### Notes

- 19. Data I/O is high impedance if  $\overline{\text{OE}} = \underline{V}_{\text{IH}}$ .

  20. If  $\overline{\text{CE}}$  goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

  21. During this period the I/Os are in the output state and <u>inp</u>ut signals should not be applied.

  22. The minimum Write cycle time for Write Cycle No. 3 (WE controlled,  $\overline{\text{OE}}$  LOW) is the sum of  $t_{\text{HZWE}}$  and  $t_{\text{SD}}$ .



## **Truth Table**

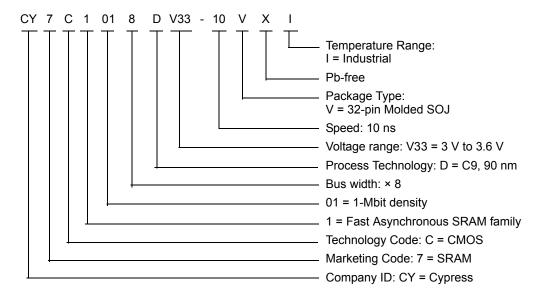
CE	OE	WE	I/O <sub>0</sub> –I/O <sub>7</sub>	Mode	Power
Н	Х	Х	High Z	Power-down	Standby (I <sub>SB</sub> )
L	L	Н	Data Out	Read	Active (I <sub>CC</sub> )
L	Х	L	Data In	Write	Active (I <sub>CC</sub> )
L	Н	Н	High Z	Selected, outputs disabled	Active (I <sub>CC</sub> )



## **Ordering Information**

	Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
Ī	10	CY7C1018DV33-10VXI	51-85041	32-pin (300-Mil) Molded SOJ (Pb-free)	Industrial

### **Ordering Code Definitions**

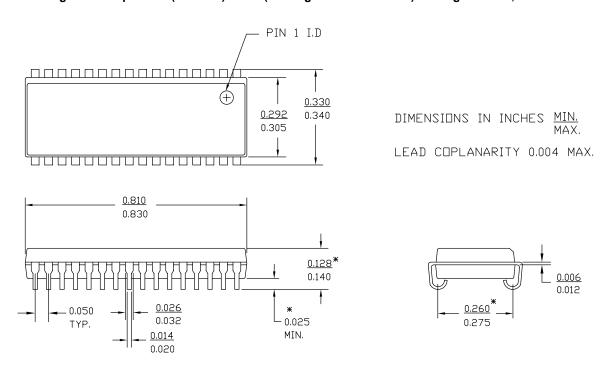


Please contact your local Cypress sales representative for availability of these parts.



## **Package Diagram**

Figure 9. 32-pin SOJ (300 Mils) V32.3 (Catalog 32.3 Molded SOJ) Package Outline, 51-85041



51-85041 \*C



# **Acronyms**

Acronym	Description		
CE	chip enable		
CMOS	complementary metal oxide semiconductor		
I/O	input/output		
ŌĒ	output enable		
SOJ	small outline J-lead		
SRAM	static random access memory		
TTL	transistor-transistor logic		
WE	write enable		

## **Document Conventions**

### **Units of Measure**

Symbol	Unit of Measure		
°C	degree Celsius		
MHz	megahertz		
μΑ	microampere		
μS	microsecond		
mA	milliampere		
ns	nanosecond		
Ω	ohm		
%	percent		
pF	picofarad		
V	volt		
W	watt		



# **Document History Page**

Documer Documer	Document Title: CY7C1018DV33, 1-Mbit (128 K × 8) Static RAM Document Number: 38-05465					
Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change		
**	201560	See ECN	SWI	Advance Information data sheet for C9 IPP		
*A	238471	See ECN	RKF	DC parameters modified as per EROS (Spec # 01-02165) Pb-free Offering in the Ordering Information		
*B	262950	See ECN	RKF	Added Data Retention Characteristics table Added T <sub>power</sub> Spec in Switching Characteristics table Shaded Ordering Information		
*C	307598	See ECN	RKF	Reduced Speed bins to -8 and -10 ns		
*D	520647	See ECN	VKN	Converted from Preliminary to Final Removed Commercial Operating range Removed 8 ns speed bin Added I <sub>CC</sub> values for the frequencies 83 MHz, 66 MHz and 40 MHz Updated Thermal Resistance table Updated Ordering Information Table Changed Overshoot spec from V <sub>CC</sub> + 2 V to V <sub>CC</sub> + 1 V in footnote #2		
*E	3104943	12/08/2010	AJU	Added Ordering Code Definitions. Updated Package Diagram.		
*F	3414435	10/19/2011	TAVA	Updated Functional Description (Removed the Note "For guidelines on SRAM system designs, please refer to the 'System Design Guidelines' Cypress application note, available on the internet at www.cypress.com." and its reference in Functional Description. Updated DC Electrical Characteristics. Updated Switching Waveforms. Updated Package Diagram. Added Acronyms and Units of Measure. Updated in new template.		

Document Number: 38-05465 Rev. \*F

Page 14 of 15



### Sales, Solutions, and Legal Information

### **Worldwide Sales and Design Support**

Cypress maintains a worldwide network of offices, solution centers, manufacturer's representatives, and distributors. To find the office closest to you, visit us at Cypress Locations.

### **Products**

Automotive
Clocks & Buffers
Interface
Lighting & Power Control

Memory
Optical & Image Sensing
PSoC
Touch Sensing
USB Controllers
Wireless/RF

cypress.com/go/automotive cypress.com/go/clocks cypress.com/go/interface cypress.com/go/powerpsoc cypress.com/go/plc

cypress.com/go/memory cypress.com/go/image cypress.com/go/psoc cypress.com/go/touch cypress.com/go/USB cypress.com/go/wireless

### **PSoC Solutions**

psoc.cypress.com/solutions PSoC 1 | PSoC 3 | PSoC 5

© Cypress Semiconductor Corporation, 2004-2011. The information contained herein is subject to change without notice. Cypress Semiconductor Corporation assumes no responsibility for the use of any circuitry other than circuitry embodied in a Cypress product. Nor does it convey or imply any license under patent or other rights. Cypress products are not warranted nor intended to be used for medical, life saving, critical control or safety applications, unless pursuant to an express written agreement with Cypress. Furthermore, Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress products in life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Any Source Code (software and/or firmware) is owned by Cypress Semiconductor Corporation (Cypress) and is protected by and subject to worldwide patent protection (United States and foreign), United States copyright laws and international treaty provisions. Cypress hereby grants to licensee a personal, non-exclusive, non-transferable license to copy, use, modify, create derivative works of, and compile the Cypress Source Code and derivative works for the sole purpose of creating custom software and or firmware in support of licensee product to be used only in conjunction with a Cypress integrated circuit as specified in the applicable agreement. Any reproduction, modification, translation, compilation, or representation of this Source Code except as specified above is prohibited without the express written permission of Cypress.

Disclaimer: CYPRESS MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARD TO THIS MATERIAL, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. Cypress reserves the right to make changes without further notice to the materials described herein. Cypress does not assume any liability arising out of the application or use of any product or circuit described herein. Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress' product in a life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Use may be limited by and subject to the applicable Cypress software license agreement.

Document Number: 38-05465 Rev. \*F Revised October 19, 2011

Page 15 of 15

# **X-ON Electronics**

Largest Supplier of Electrical and Electronic Components

Click to view similar products for SRAM category:

Click to view products by Cypress manufacturer:

Other Similar products are found below:

CY6116A-35DMB CY7C1049GN-10VXI CY7C128A-45DMB GS8161Z36DD-200I GS88237CB-200I RMLV0408EGSB-4S2#AA0

IDT70V5388S166BG IS64WV3216BLL-15CTLA3 IS66WVE4M16ECLL-70BLI PCF8570P K6F2008V2E-LF70000 K6T4008C1B-GB70

CY7C1353S-100AXC AS6C8016-55BIN AS7C164A-15PCN 515712X IDT71V67603S133BG IS62WV51216EBLL-45BLI

IS63WV1288DBLL-10HLI IS66WVE2M16ECLL-70BLI 70V639S10BCG IS66WVE4M16EALL-70BLI IS62WV6416DBLL-45BLI

IS61WV102416DBLL-10TLI CY7C1381KV33-100AXC CY7C1381KVE33-133AXI 8602501XA 5962-3829425MUA 5962-3829430MUA

5962-8855206YA 5962-8866201YA 5962-8866204TA 5962-8866206MA 5962-8866208UA 5962-8872502XA 5962-9062007MXA 5962-8871202XA 5962-8872501LA 5962-8866208YA 5962-8866205YA 5962-8866205UA 5962-8866203YA 5962-8855202YA